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U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. 34170

SERIAL NO. 10/672,210

NFORMATION DISCLOSURE STATEMENT BY APPLICANT

se several sheets if necessary)

APPLICANT: Maurice Lee Smith et al.

FILING DATE:

GROUP:

9/26/2003

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U.S. PATENT DOCUMENTS

EXAM. INITIAL		DOC	CUME	ENT	NUM	BER		DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
4	6	6	2	8	9	4	1	9/30/03	Knoblach et al.			
ı	6	6	9	8	5	5	9	8/19/03	Lemelson et al.			
i.	6	5	8	8	7	0	1	7/08/03	Yavnal	¢		
i	6	4	9	в	0	4	1	12/24/02	Tabacco et al.	,		
1	6	4	9	0	5	3	0	12/03/02	Wyatt			
1	6	4	4	6	0	0	4	9/03/02	Cao et al.			
î	6	3	5	6	6	2	5	3/12/02	Castellani et al.			
î	6	3	2	7	5	3	5	12/04/01	Evans et al.			
1	6	3	1	7	0	8	0	11/13/01	Baxter, Jr.			
Į	6	1	6	9	4	7	6	01/02/01	Flanagan			
1	6	0	8	3	2	4	8	7/04/00	Тһотрѕоп			
1	6	9	7	5	8	9	1	6/13/00	Burman			
-	6	0	5	2	1	8	7	4/18/00	Krishnan et al.			
1	6	G	2	3	2	2	3	2/08/00	Baxter, Jr.			
1	5	9	7	2	6	3	8	10/26/99	Burlage et al.			
ţ	5	9	3	8	7	2	1	8/17/99	Dussell et al.			
-	5	8	3	Θ	2	3	7	11/17/98	Revell et al.			
ì	5	6	5	0	8	٥	9	7/22/97	Benson			
-	5	6	4	8	9	1	4	7/15/97	Bauer et al.			
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	4	8	6	1	7	2	7	8/29/89	Hauenstein et al.			
			н	1	3	4	4	4/02/94	Baldauf et al.			
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FOREIGN PATENT DOCUMENTS

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FORM PTO-1449 (Rev. 2-32)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO. 33063 SERIAL NO. 10/672,21 ©		
	DRMATION DISCLOSURE TEMENT BY APPLICANT	APPLICANT: Maurice Lee Smith et al.		
(Use s	several sheets if necessary)	FILING DATE: 9/26/2003	GROUP: 2878	

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

į	"Oak Ridge claims sensitivity record for Si MEMS sensor"; June 23, 2003 article in Electronic Engineering Times; Author R. Colin Johnson, page 49.

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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